

ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of
Invention

METHODS AND SYSTEMS FOR INSPECTION OF AN
ENTIRE WAFER SURFACE USING MULTIPLE
DETECTION CHANNELS.

Application Number: 10/663603



Confirmation Number: 3534

First Named Applicant: Lionel Kuhlmann








Attorney Docket Number: 5589-06100

Search string: (6271916 or 6204917 or 6559938 or 6201601
or 6538730 or 6509965 or 6507394 or 6356346
or 6020957 or 5355212 or 6407809 or 6515742
or 6496256 or 6034776 or 5999266 or 5801824
or 5623340 or 5604585 or 5585916 or 4632546
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US Patent Documents






Note: Applicant is not required to submit a paper copy of cited US Patent Documents

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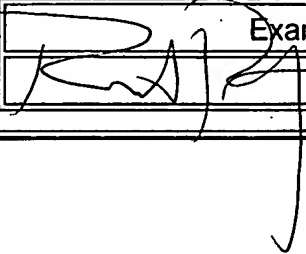
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Signature

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